SN54AHCT132, SN74AHCT132 QUADRUPLE POSITIVE-NAND GATES WITH SCHMITT-TRIGGER INPUTS

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- Inputs Are TTL-Voltage Compatible
- Operation From Very Slow Input Transitions
- Temperature-Compensated Threshold Levels
- High Noise Immunity
- Same Pinouts as 'AHCT00
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)

description

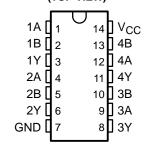
The 'AHCT132 devices are quadruple positive-NAND gates.

These devices perform the Boolean function $Y = \overline{A \cdot B}$ or $Y = \overline{A} + \overline{B}$ in positive logic.

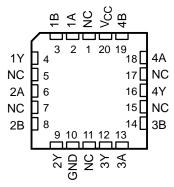
Each circuit functions as a NAND gate, but because of the Schmitt action, it has different input threshold levels for positive- and negative-going signals.

These circuits are temperature compensated and can be triggered from the slowest of input ramps and still give clean jitter-free output signals.

SN54AHCT132 . . . J OR W PACKAGE SN74AHCT132 . . . D, DB, DGV, N, NS, OR PW PACKAGE (TOP VIEW)



SN54AHCT132...FK PACKAGE (TOP VIEW)



NC - No internal connection

ORDERING INFORMATION

T _A PACKAGE [†]		GE†	ORDERABLE PART NUMBER	TOP-SIDE MARKING
	PDIP – N	Tube	SN74AHCT132N	SN74AHCT132N
	SOIC - D	Tube	SN74AHCT132D	AHCT132
–40°C to 85°C	3010-15	Tape and reel	SN74AHCT132DR	A1101132
	SOP – NS	Tape and reel	SN74AHCT132NSR	AHCT132
	SSOP – DB	Tape and reel	SN74AHCT132DBR	HB132
	TSSOP – PW	Tape and reel	SN74AHCT132PWR	HB132
	TVSOP – DGV	Tape and reel	SN74AHCT132DGVR	HB132
	CDIP – J	Tube	SNJ54AHCT132J	SNJ54AHCT132J
–55°C to 125°C	CFP – W	Tube	SNJ54AHCT132W	SNJ54AHCT132W
	LCCC – FK	Tube	SNJ54AHCT132FK	SNJ54AHCT132FK

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



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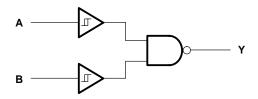
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FUNCTION TABLE (each gate)

INP	UTS	OUTPUT
Α	В	Y
Н	Н	L
L	X	Н
Х	L	Н

logic diagram, each gate (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}		
Output voltage range, VO (see Note 1)		-0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$)		
Output clamp current, IOK (VO < 0 or VO > VCO	c)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})		±25 mA
Continuous current through V _{CC} or GND		±50 mA
Package thermal impedance, θ _{JA} (see Note 2)	: D package	86°C/W
	DB package	96°C/W
	DGV package	
	N package	80°C/W
	NS package	76°C/W
	PW package	113°C/W
Storage temperature range, T _{stq}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The package thermal impedance is calculated in accordance with JESD 51-7.



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recommended operating conditions (see Note 3)

		SN54AHCT132		SN74AH	UNIT	
		MIN	MIN MAX		MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
٧ı	Input voltage	0	5.5	0	5.5	V
٧o	Output voltage	0	Vcc	0	VCC	٧
ЮН	High-level output current	5	-8		-8	mA
loL	Low-level output current	Q _C	8		8	mA
TA	Operating free-air temperature	– 55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	T,	λ = 25°C	;	SN54AHCT132		SN74AHCT132		UNIT	
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
V _{T+}		4.5 V	0.9		1.9	0.9	1.9	0.9	1.9	V	
Positive-going input threshold voltage		5.5 V	1		2.1	1	2.1	1	2.1	V	
VT-		4.5 V	0.5		1.5	0.5	1.5	0.5	1.5	V	
Negative-going input threshold voltage		5.5 V	0.6		1.7	0.6	1.7	0.6	1.7	V	
ΔVT		4.5 V	0.3		1.4	0.3	1.4	0.3	1.4	V	
Hysteresis (V _{T+} – V _T –)		5.5 V	0.3		1.5	0.3	1.5	0.3	1.5	V	
Vari	IOH = -50 μA	4.5 V	4.4	4.5		4.4		4.4		V	
VOH	I _{OH} = -8 mA	4.5 V	3.94			3.8		3.8			
Voi	I _{OL} = 50 μA	4.5 V	4.5.\/			0.1	08	0.1		0.1	V
VOL	I _{OL} = 8 mA				0.36	V	0.5		0.44	'	
lį	V _I = 5.5 V or GND	0 V to 5.5 V			±0.1		±1*		±1	μΑ	
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			2		20		20	μΑ	
ΔICC [†]	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35		1.5		1.5	mA	
Ci	V _I = V _{CC} or GND	5 V		2	10				10	pF	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested at $V_{CC} = 0 \text{ V}$.

[†] This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

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switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD CAPACITANCE	T _A = 25°C		SN54AHCT132		SN74AHCT132		UNIT												
PARAMETER	(INPUT)	(OUTPUT)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT											
^t PLH	A or B	Y	C _I = 15 pF	C: 45 pF		5.5*	8*	1*	9*	1	9	no										
t _{PHL}	AUB		l l	'	•	•			'	1 OL = 1	'	ľ	CL = 13 pr		ι <u>CL = 13 p</u> ι		4.5*	6*	1*	7*	1	7
tPLH	A or B	V	C 50 pF		6.5	9	10	10	1	10	20											
t _{PHL}	AUB	ſ	C _L = 50 pF		5.5	7	Q 1	8	1	8	ns											

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

noise characteristics, $V_{CC} = 5 \text{ V}$, $C_L = 50 \text{ pF}$, $T_A = 25^{\circ}\text{C}$ (see Note 4)

	PARAMETER		SN74AHCT132		
			TYP	MAX	UNIT
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.5	0.8	V
V _{OL} (V)	Quiet output, minimum dynamic V _{OL}		-0.28	-0.8	V
VOH(V)	Quiet output, minimum dynamic VOH		5		V
VIH(D)	High-level dynamic input voltage	2			V
V _{IL(D)}	Low-level dynamic input voltage			0.8	V

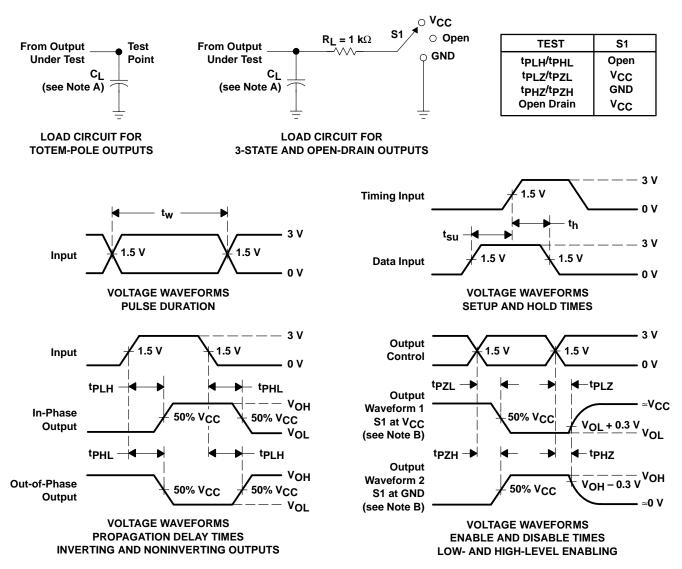
NOTE 4: Characteristics are for surface-mount packages only.

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
Ī	C _{pd} Power dissipation capacitance	No load, f = 1 MHz	15	pF

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_Q = 50 \Omega$, $t_f \leq$ 3 ns, $t_f \leq$ 3 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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